

Search Notes

Application/Control No.

10/664,740

Examiner

Maikhanh Nguyen

Applicant(s)/Patent under
Reexamination

YALOVSKY ET AL.

Art Unit

2176

SEARCHED

| Class | Subclass | Date | Examiner |
|---------|----------|-----------|----------|
| 715 | 530 | 2/14/2006 | MK |
| 715 | 526 | 2/14/2006 | MK |
| 709 | 219,229 | 2/14/2006 | MK |
| Updated | Search | 10/6/2006 | MK |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| Inventor Name Search | 2/14/2006 | |
| West Search (USPAT, USPGPub, EPO, JPO, DERWENT) See Search History Printout | 2/14/2006 | MK |
| West Updated | 10/6/2006 | MK |
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